

# **MOSFET** – Power, N-Channel, Automotive, SUPERFET<sup>®</sup> III, Easy-Drive

## 650 V, 25 m $\Omega$

## **NVCR8LS025N65S3A**

#### **Features**

- Typical  $R_{DS(on)}$  = 19.9 m $\Omega$  at  $V_{GS}$  = 10 V
- Typical  $Q_{g(tot)} = 236 \text{ nC}$  at  $V_{GS} = 10 \text{ V}$
- AEC-Q101 Qualified
- RoHS Compliant

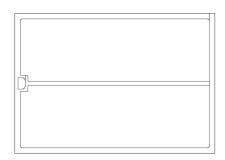
#### DIMENSION (µm)

Die Size	10830 x 7610
Die Size (Sawn)	10810 ±30 x 7590 ±30
Source Attach Area	(10155 x 3346) x 2
Gate Attach Area	406 x 618
Die Thickness	$203.2 \pm 25.4$

Gate and Source: AlSiCu

Drain: Ti-NiV-Ag (back side of die)

Passivation: SiN Wafer Diameter: 8 inch Wafer sawn on UV Tape Bad dice identified in Inking Gross Die Count: 296



#### **ORDERING INFORMATION**

Device	Package
NVCR8LS025N65S3A	Wafer Sawn on Foil

#### RECOMMENDED STORAGE CONDITIONS

Temperature	22 to 28°C		
RH	40% to 66%		

#### **ELECTRICAL CHARACTERISTICS**

The Chip is 100% Probed to Meet the Conditions and Limits Specified at  $T_J$  = 25°C

Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	650	-	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V	_	-	1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = +30 / -20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 3 \text{ mA}$	2.5	-	4.5	V
*R <sub>DS(on)</sub>	Bare Die Drain to Source On Resistance	I <sub>D</sub> = 37.5 A, V <sub>GS</sub> = 10 V	-	19.9	25	mΩ
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 37.5 V			1.2	V

<sup>\*</sup>Accurate RDS(on) test at die level is not feasible for this thin die as limited by the test contact precision attainable in a die form. The max RDS(on) specification is defined from the historical performance of the die in package but is not guaranteed by test in production. The die RDS(on) performance depends on the Source wire/ribbon bonding layout.

#### **ABSOLUTE MAXIMUM RATINGS**

in Reference to the NVHL025N65S3 electrical data in TO-247-3LD (  $T_J$  = 25°C unless otherwise noted)

Symbol	Parameter		Ratings	Unit	
V <sub>DSS</sub>	Drain to Source Voltage		650	V	
V <sub>GS</sub>	Gate to Source Voltage	DC Positive	30	V	
		AC Positive, (f > 1Hz)	30	V	
		AC Negative, (f > 1Hz)	-20	V	
$I_{D}$	Continuous Drain Current	$T_C = 25^{\circ}C$	75	Α	
		$T_C = 100^{\circ}C$	65.8	Α	
I <sub>DM</sub>	Pulsed Drain Current	Pulsed (Note 1)	300	Α	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)		2025	mJ	
E <sub>AR</sub>	Repetitive Avalanche (Note 1)		5.95	mJ	
dv/dt	MOSFET dv/dt		100	V/ns	
	Peak Diode Recovery dv/dt (Note 3)		20	V/ns	
P <sub>D</sub>	Power Dissipation R <sub>θJC</sub>	$T_C = 25^{\circ}C$	595	W	
T <sub>J,</sub> T <sub>STG</sub>	Operating and Storage Temperature		-55 to +150	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive rating: pulse–width limited by maximum junction temperature. 2.  $I_{AS}=15$  A,  $R_{G}=25$   $\Omega$ , Starting  $T_{J}=25^{\circ}C$ . 3.  $I_{SD}<75$  A, di/dt  $\leq 200$  A/ms, VDD  $\leq$  BVDSS, starting  $T_{J}=25^{\circ}C$

#### THERMAL CHARACTERISTICS

Symbol	Symbol Parameter		Unit	
R <sub>θJ C</sub> Thermal Resistance, Junction to Case, Max		0.21	°C/W	
$R_{ heta J A}$	Thermal Resistance, Junction to Ambient, Max	40	°C/W	

#### **ELECTRICAL CHARACTERISTICS**

in Reference to the NVHL025N65S3 electrical data in TO-247-3LD (  $T_J$  = 25°C unless otherwise noted)

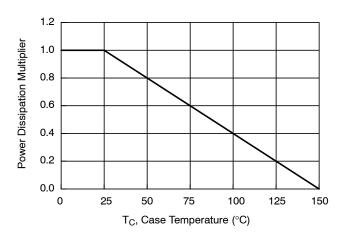
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
OFF CHA	RACTERISTICS	<u> </u>	•	•		-
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0 V	650	-	_	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 25°C	-	-	1	μА
	V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125°C	-	7.92	-	μА	
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = +30 V	-	-	+100	nA
		V <sub>GS</sub> = -20 V			-100	nA
ON CHAR	ACTERISTICS			-	•	
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 3.0 \text{ mA}$	2.5		4.5	V
R <sub>DS(on)</sub>	Drain to Source On-Resistance	$I_D = 37.5 \text{ A}, \qquad T_J = 25^{\circ}\text{C}$	-	19.9	25	mΩ
, ,		V <sub>GS</sub> = 10 V T <sub>J</sub> = 100°C	-	34.6	-	mΩ
9FS	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 75 A		78.5		S
DYNAMIC	CHARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V,	-	7330	-	pF
C <sub>oss</sub>	Output Capacitance	f = 1 MHz	_	197	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		_	33.6	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		2062		pF
C <sub>oss(er.)</sub>	Energy Related Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		285		pF
Q <sub>g(ToT)</sub>	Total Gate Charge	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 400 V <sub>,</sub> I <sub>D</sub> = 75 A	-	236	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 4)	-	59.3	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		_	97.3	-	nC
RG	Gate Resistance	f = 1 MHz	-	0.818	-	Ω
SWITCHI	NG CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, \ I_D = 75 \text{ A}, V_{GS} = 10 \text{ V},$	-	43.3	-	ns
t <sub>r</sub>	Rise Time	$R_G = 2 \Omega$	-	109	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(Note 4)	_	120	-	ns
t <sub>f</sub>	Fall Time		_	107	-	ns
DRAIN - S	SOURCE DIODE CHARACTERISTICS					
Is	Maximum Continuous Drain to Source Diode Forward Current				75	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current				300	Α
V <sub>SD</sub>	Source to Drain Diode Voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 37.5 \text{ A}, V_{GS} = 0 \text{ V}$	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS}$ = 0 V, $I_{SD}$ = 75 A, $dI_{SD}/dt$ = 100 A/ $\mu s$	-	714	_	ns
			_	26.4		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

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#### **TYPICAL CHARACTERISTICS**



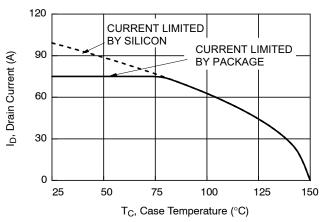


Figure 1. Normalized Power Dissipation vs. Case Temperature

Figure 2. Maximum Continuous Drain Current vs. Case Temperature

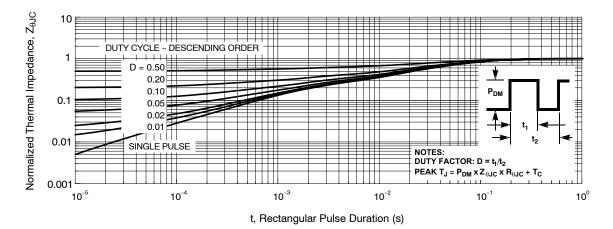


Figure 3. Normalized Maximum Transient Thermal Impedance

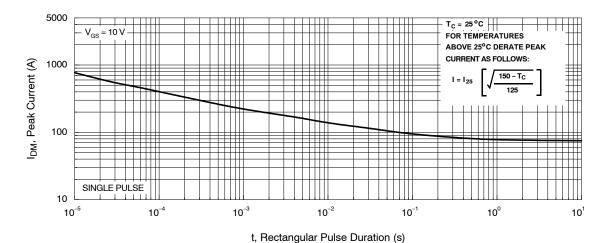


Figure 4. Peak Current Capability

#### TYPICAL CHARACTERISTICS (continued)

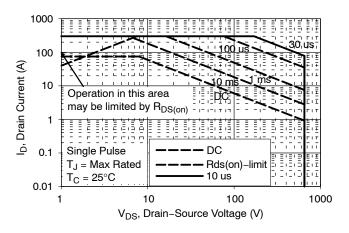


Figure 5. Forward Bias Safe Operating Area

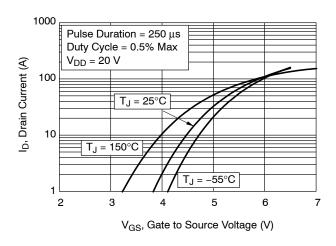


Figure 6. Transfer Characteristic

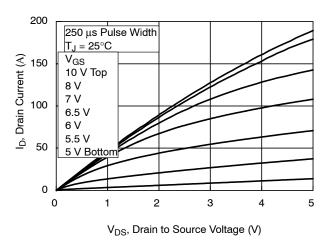


Figure 8. Saturation Characteristics

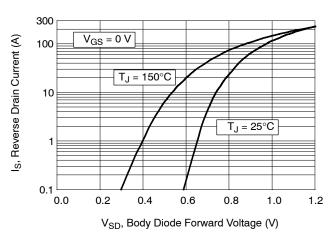


Figure 7. Forward Diode Characteristics

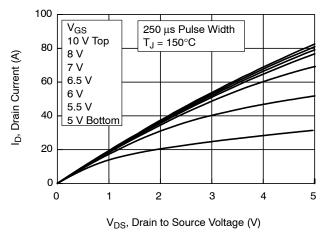
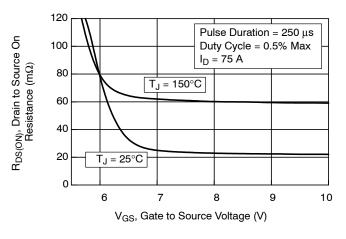


Figure 9. Saturation Characteristics

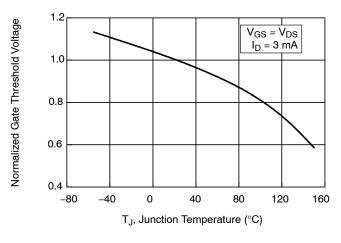
#### TYPICAL CHARACTERISTICS (continued)



3.0 Pulse Duration = 250 μs Normalized Drain to Source 2.5 Duty Cycle = 0.5% Max ON-Resistance 2.0 1.5  $I_D = 75 A$ 1.0 V<sub>GS</sub> = 10 V 0.5 0.0 -80 -40 40 80 120 160 T<sub>J</sub>, Junction Temperature (°C)

Figure 10. R<sub>DSON</sub> vs. Gate Voltage

Figure 11. Normalized R<sub>DSON</sub> vs. Junction Temperature



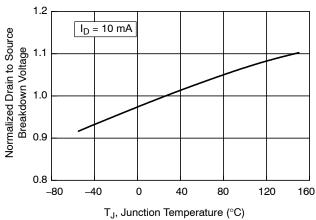
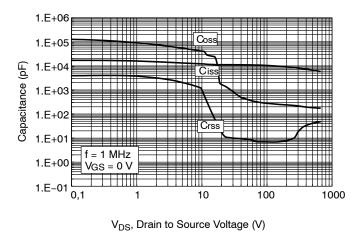


Figure 12. Normalized Gate Threshold Voltage vs. Temperature

Figure 13. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature



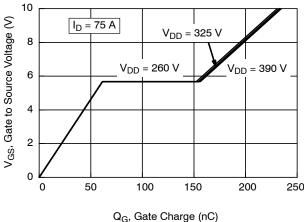


Figure 14. Capacitance vs. Drain to Source Volatage

Figure 15. Gate Charge vs. Gate to Source Voltage

## TYPICAL CHARACTERISTICS (continued)

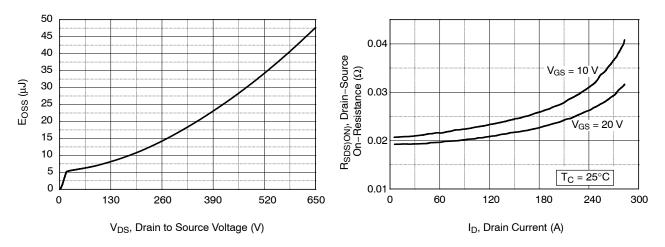


Figure 16. E<sub>OSS</sub> vs. Drain to Source Voltage

Figure 17. On–Resistance Variation vs. Drain Current and Gate Voltage

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